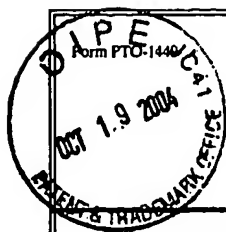


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U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY. DOCKET NO.
M140-369SERIAL NO.
10/734,072LIST OF ART CITED BY APPLICANT
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Mark E. Tuttle et al.FILING DATE
December 10, 2003GROUP
2825

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
CME	AK	7-200766 A	08/95	JP - Application	—	—	X	
CME	AL	8-96090 A	04/96	JP - Application	—	—	X	
CME	AM	8-111573	04/96	JP - Abstract	—	—		
	AN							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AO		
	AP		
EXAMINER	C. J. J. J.	DATE CONSIDERED	12-14-04

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Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI40-369	SERIAL NO. <u>10/734/072</u> UNASSIGNED			
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT MICRON TECHNOLOGY, INC.				
				FILING DATE <u>12/10/03</u> FILED HEREWITH		GROUP <u>2825</u> UNASSIGNED		
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>CME</i>	AA	3,701,317	10/1972	MIYAMOTO ET AL.	101	170		
	AB	3,981,761	9/1976	KOJIMA ET AL.	156	235		
	AC	4,075,632	2/1978	BALDWIN ET AL.	343	68 R		
	AD	4,135,184	1/1979	PRUZICK	340	572		
	AE	4,232,512	11/1980	YOSHIKAWA ET AL.	368	82		
	AF	4,926,182	5/15/90	OHTA ET AL.	342	44		
	AG	5,148,355	9/1992	LOWE ET AL.	361	410		
	AH	5,402,095	3/28/95	JANNIERE	235	441		
	AI	5,412,192	5/1995	HOSS	235	380		
	AJ	5,428,214	6/1995	HAKKERS ET AL.	235	492		
<i>CME</i>	AK	5,528,222	6/1996	MOSKOWITZ ET AL.	340	572		
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>CME</i>	AL	WO 96/07985	3/1996	PCT	—	—		
<i>CME</i>	AM	O 682 321	5/1995	Europe	—	—		
<i>CME</i>	AN	DE 4431605	3/1996	German	—	—		
<i>CME</i>	AO	DE 3201065	7/1993	German	—	—		
<i>CME</i>	AP	WO 90 07858	7/1990	PCT	—	—		
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR							
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EXAMINER <i>C. Juerhard</i>				DATE CONSIDERED <u>12-14-04</u>				
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U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
<i>CME</i>	AA	5,598,032	1/1997	FIDALGO	257	679	
	AB	5,600,175	2/1997	ORTHMANN	257	532	
	AC	5,621,412	4/1997	SHARPE ET AL.	342	51	
	AD	5,647,122	7/1997	LAUNAY ET AL.	29	840	
	AE	5,649,296	7/15/97	MACLELLAN ET AL.	455	38.2	
	AF	5,729,053	3/1998	ORTHMANN	257	724	
	AG	5,735,040	4/1998	OCHI ET AL.	29	841	
	AH	5,850,690	12/1998	LAUNAY ET AL.	29	841	
	AI	5,880,934	3/1999	HAGHIRI-TEHRANI	361	737	
	AJ	5,880,937	3/1999	SCHADHAUSER ET AL.	361	794	
<i>CME</i>	AK	6,130,602	10/2000	O'TOOLE ET AL.	340	10.33	
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
<i>CME</i>	AL	8-138022	JAPAN			x	
	AM						
	AN						
	AO						
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AR						
	AS						
	AT						
EXAMINER <i>C. Juerhart</i>				DATE CONSIDERED <i>12-14-04</i>			
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